Se	arc	ch Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/597,676	TANAKA ET AL.	
Examiner	Art Unit	
Chandrika Prasad	2839	

	SEARCHED			
	SEARCHED			
Class	Subclass	Date	Examiner	
439	326	8/26/2007	СР	
	630			
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i.	159			
	862			
	331			
	260			
235	492			
361	737			

INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH (INCLUDING SEA	I NOTES	S RATEGY	')
	•	DATE	EXMR
BRS TEXT SEARCH		8/26/2007	СР